

Notice of References Cited	Application/Control No. 10/616,525	Applicant(s)/Patent Under Reexamination FUNK ET AL.	
	Examiner J. Derek Rutten	Art Unit 2192	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0042226 A1	11-2001	Dzoba et al.	714/39
*	B	US-5,533,192 A	07-1996	Hawley et al.	714/28
*	C	US-5,768,500 A	06-1998	Agrawal et al.	714/47
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bickle et al., "Differential Effective Lapse Time Accumulator (Delta)", July 1 1984, IBM Technical Disclosure Bulletin, Volume 27, Issue 2, pp: 1258-1259
	V	Rosenberg, "How Debuggers Work", 1996, John Wiley & Sons, Chapters 1-3
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.